

3N187

**Silicon Dual Insulated-Gate
Field-Effect Transistor**

With Integrated Gate-Protection Circuits

For Military and Industrial Applications up to 300 MHz

Device Features

- Back-to-back diodes protect each gate against handling and in-circuit transients
- High forward transconductance — $g_{fs} = 12,000 \mu\text{mho}$ (typ.)
- High unneutralized RF power gain — $G_{ps} = 18 \text{ dB}$ (typ.) at 200 MHz
- Low VHF noise figure — 3.5 dB (typ.) at 200 MHz

Applications

- RF amplifier, mixer, and IF amplifier in military, and industrial communications equipment
- Aircraft and marine vehicular receivers
- CATV and MATV equipment
- Telemetry and multiplex equipment

Performance Features

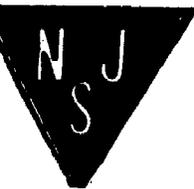
- Superior cross-modulation performance and greater dynamic range than bipolar or single-gate FET's
- Wide dynamic range permits large-signal handling before overload
- Virtually no agc power required
- Greatly reduces spurious responses in FM receivers

Maximum Ratings,

Absolute-Maximum Values, at $T_A = 25^\circ\text{C}$

| | | |
|---|--------------------------|------------------|
| DRAIN-TO-SOURCE VOLTAGE, V_{DS} . . . | -0.2 to +20, | V |
| GATE No. 1-TO-SOURCE VOLTAGE, V_{G1S} : | | |
| Continuous (dc) | -6 to +3 | V |
| Peak ac | -6 to +6 | V |
| GATE No. 2-TO-SOURCE VOLTAGE, V_{G2S} : | | |
| Continuous (dc) | -6 to 30% of V_{DS} | V |
| Peak ac | -6 to +6 | V |
| * DRAIN-TO-GATE VOLTAGE, | | |
| V_{DG1} OR V_{DG2} | +20 | V |
| * DRAIN CURRENT, I_D | 50 | mA |
| * TRANSISTOR DISSIPATION P_T : | | |
| At ambient } up to 25°C | 330 | mW |
| temperatures } above 25°C | derate linearly at | |
| | 2.2 mW/ $^\circ\text{C}$ | |
| * AMBIENT TEMPERATURE RANGE: | | |
| Storage and Operating | -85 to +175 | $^\circ\text{C}$ |
| * LEAD TEMPERATURE (During Soldering): | | |
| At distances $\geq 1/32$ inch from | | |
| seating surface for 10 seconds max. | 265 | $^\circ\text{C}$ |

* In accordance with JEDEC Registration Data Format JS-9 RDF-19A



ELECTRICAL CHARACTERISTICS, at $T_A = 25^\circ\text{C}$ unless otherwise specified

| CHARACTERISTICS | SYMBOL | TEST CONDITIONS | LIMITS | | | UNITS |
|--|------------------------------------|--|---------------------------|-----------------|--------|-----------------|
| | | | Min. | Typ. | Max. | |
| * Gate No. 1-to-Source Cutoff Voltage | $V_{G1S(off)}$ | $V_{DS} = +15\text{ V}, I_D = 50\ \mu\text{A}$ $V_{G2S} = +4\text{ V}$ | -0.5 | -2 | -4 | V |
| * Gate No. 2-to-Source Cutoff Voltage | $V_{G2S(off)}$ | $V_{DS} = +15\text{ V}, I_D = 50\ \mu\text{A}$ $V_{G1S} = 0$ | -0.5 | -2 | -4 | V |
| * Gate No. 1-Terminal Forward Current | I_{G1SSF} | $V_{G1S} = +1\text{ V}$ $V_{G2S} = V_{DS} = 0$ | $T_A = 25^\circ\text{C}$ | | 50 | nA |
| | | | $T_A = 100^\circ\text{C}$ | | 5 | μA |
| * Gate No. 1-Terminal Reverse Current | I_{G1SSR} | $V_{G1S} = -6\text{ V}$ $V_{G2S} = V_{DS} = 0$ | $T_A = 25^\circ\text{C}$ | | 50 | nA |
| | | | $T_A = 100^\circ\text{C}$ | | 5 | μA |
| * Gate No. 2-Terminal Forward Current | I_{G2SSF} | $V_{G2S} = +6\text{ V}$ $V_{G1S} = V_{DS} = 0$ | $T_A = 25^\circ\text{C}$ | | 50 | nA |
| | | | $T_A = 100^\circ\text{C}$ | | 5 | μA |
| * Gate No. 2-Terminal Reverse Current | I_{G2SSR} | $V_{G2S} = -6\text{ V}$ $V_{G1S} = V_{DS} = 0$ | $T_A = 25^\circ\text{C}$ | | 50 | nA |
| | | | $T_A = 100^\circ\text{C}$ | | 5 | μA |
| * Zero-Bias Drain Current | I_{DS} | $V_{DS} = +15\text{ V}$ $V_{G2S} = +4\text{ V}$ $V_{G1S} = 0$ | 5 | 15 | 30 | mA |
| Forward Transconductance (Gate No. 1-to-Drain) | g_{fs} | $V_{DS} = +15\text{ V}, I_D = 10\text{ mA}$ $V_{G2S} = +4\text{ V}, f = 1\text{ kHz}$ | 7000 | 12,000 | 18,000 | μmho |
| * Small-Signal, Short-Circuit Input Capacitance† | C_{iss} | $V_{DS} = +15\text{ V}, I_D = 10\text{ mA}$ $V_{G2S} = +4\text{ V}, f = 1\text{ MHz}$ | 4.0 | 6.0 | 8.5 | pF |
| * Small-Signal, Short-Circuit, Reverse Transfer Capacitance (Drain-to-Gate No. 1)‡ | C_{rss} | | 0.005 | 0.02 | 0.03 | pF |
| * Small-Signal, Short-Circuit Output Capacitance | C_{oss} | | - | 2.0 | - | pF |
| Power Gain (see Fig. 1) | G_{PS} | $V_{DS} = +15\text{ V}, I_D = 10\text{ mA}$ $V_{G2S} = +4\text{ V}, f = 200\text{ MHz}$ | 16 | 18 | 22 | dB |
| Maximum Available Power Gain | MAG | | - | 20 | - | dB |
| Maximum Usable Power Gain (unneutralized) | MUG | | - | 20 ^Δ | - | dB |
| Noise Figure (see Fig. 1) | NF | | - | 3.5 | 4.5 | dB |
| * Magnitude of Forward Transadmittance | $ Y_{fs} $ | | - | 12,000 | - | μmho |
| * Phase Angle of Forward Transadmittance | θ | | - | -35 | - | Degrees |
| Magnitude of Reverse Transadmittance | $ Y_{rs} $ | | - | 25 | - | μmho |
| Angle of Reverse Transadmittance | θ_{rs} | | - | -25 | - | Degrees |
| * Input Resistance | r_{iss} | | - | 1.0 | - | k Ω |
| * Output Resistance | r_{oss} | | - | 2.8 | - | k Ω |
| * Gate-to-Source Forward Breakdown Voltage: Gate No. 1 Gate No. 2 | $V_{(BR)G1SSF}$ $V_{(BR)G2SSF}$ | $I_{G1SSF} = I_{G2SSF} = 100\ \mu\text{A}$ | 6.5 | 10 | - | V |
| * Gate-to-Source Reverse Breakdown Voltage: Gate No. 1 Gate No. 2 | $V_{(BR)G1SSR}$ $V_{(BR)G2SSR}$ | $I_{G1SSR} = I_{G2SSR} = -100\ \mu\text{A}$ | -6.5 | -10 | - | V |

^Δ Limited only by practical design considerations.

† Capacitance between Gate No. 1 and all other terminals

‡ Three-terminal measurement with Gate No. 2 and Source returned to ground terminal.

* In accordance with JEDEC Registration Data Format J5-9 RDP-19A

OPERATING CONSIDERATIONS

The flexible leads of the 3N187 are usually soldered to the circuit elements. As in the case of any high-frequency semiconductor device, the tips of soldering irons MUST be grounded.